

AMENDMENTS TO THE CLAIMS:

Replace the claims with the following rewritten listing:

1. (Previously Presented) An apparatus for planning preparing, performing and evaluating a non-destructive inspection of a test object having various test regions, wherein at least some of the test regions require different suitable test instruments for testing the test regions, said apparatus having one or more discretionary suitable test instruments and comprising:
 - an input device,
 - an output device,
 - a data store,
 - a data processing unit,
 - an interface for connecting a respective one of the test instruments through which data are adapted to be transmitted in both directions,
 - a standardized data processing program for
 - defining a test object by data input or selecting it from the data store,
 - determining various test regions of a test object,
 - selecting at least one determined test instrument from a group of test instruments for each of the test regions requiring different suitable test instruments and associating each with a respective one of the test regions, with all relevant properties of the test instrument being stored in the data store,
 - carrying out test-relevant settings for the selected instrument,
 - selecting a kind of visualization and evaluation of measured test values,
 - archiving and storing test results obtained,
 - establishing a test scheme, with all predetermined settings being transferred to the respective test instrument upon connection thereof so that it is preset for inspection.

2. (Previously Presented) The apparatus as set forth in claim 1, wherein additional instruments are selectable through the standardized data processing program and may be associated.
3. (Previously Presented) The apparatus as set forth in claim 1, wherein all the selectable data are represented by standardized plugins that may be combined together by virtue of a standardized interface.
4. (Previously Presented) The apparatus as set forth in claim 3, wherein the possibility of combining the plugins, or rather the modular structure, is given by a "Common Application Architecture" (CAA) which is based on a "Universal Application Framework" (UAF).
5. (Previously Presented) The apparatus as set forth in claim 4, wherein visualization and evaluation of the test values obtained may occur both online and offline.
6. (Previously Presented) The apparatus as set forth in claim 5, wherein a user interface, which is configured in the fashion of a Windows interface and in which the test scheme may be established, based on the plugins, is disposed on the output device.
7. (Previously Presented) The apparatus as set forth in claim 6, wherein the plugins are selectable with the help of a moving function and may be associated.
8. (Previously Presented) The apparatus as set forth in claim 1, wherein the test instruments are implemented to be ultrasonic test instruments.
9. (Currently Amended) A method for carrying out a non-destructive inspection-with help of an apparatus as set forth in claim 1, the method comprising:
providing an apparatus for planning preparing, performing and evaluating a non-destructive inspection of a test object having various test regions, wherein at least

some of the test regions require different suitable test instruments for testing the test regions, said apparatus having one or more discretionary suitable test instruments and an input device, an output device, a data store, a data processing unit, an interface for connecting a respective one of the test instruments through which data are adapted to be transmitted in both directions, and a standardized data processing program;

inputting or selecting relevant data of a test object,
determining test regions,
selecting test instruments or probes suited for the test regions,
selecting a manner of visualizing and evaluating measured test values,
selecting a manner of storing and archiving the test results.

10. (Previously Presented) The method as set forth in claim 9, wherein an inspection scheme can be established in which the order in which the respective test instruments or probes are used for inspection can be fixed.
11. (Previously Presented) The method as set forth in claim 9, wherein further additional instruments are selected.